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Microscopy research has never been so easy before!

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WEBINARS

Date	Time	Topic
May 20, 2020	11:00am CEST	Advanced High Vacuum Magnetic Force Microscopy (MFM): study of topological spin textures
May 22, 2020	12:00pm EDT	4D Printing and Stimuli Response
May 27, 2020	11:00am CEST	Advances in Scanning Capacitance Microscopy for Electrical Nanocharacterization and Failure Analysis (PinPoint™ and QuickStep™)
May 27, 2020	12:00pm EDT	Electrochemical AFM (EC-AFM): Copper Deposition/Dissolution on Gold
June 10, 2020	11:00am CEST	Advanced Piezoresponse Force Microscopy - optimizing PFM for your applications from off resonance to frequency tracking
June 17, 2020	11:00am CEST	Photovoltaic effect in ferroelectric materials

Live Demos

Date	Time	Topic
April 15, 2020	10:30am CEST	Quick automation set-up for research applications (SmartScan™ & StepScan™)
April 17, 2020	12:00pm PDT	SmartScan Topography Imaging
April 22, 2020	10:30am CEST	From automatization in research to quality control
April 24, 2020	15:00pm EDT	SmartScan Advanced KPFM Imaging
May 6, 2020	16:00pm CEST	Full-automation in-line capabilities with the NX-Wafer

RECORDINGS AVAILABLE SOON

WEBINAR RECORDINGS

Topic
Conductive Atomic Force Microscopy used for Two-Dimensional Materials and Nanoelectronics (Chinese)
Nanotechnology in Plastics and Packaging
Surface Plasmon Resonance Spectroscopy Tandem with AFM
Unraveling Amyloid Formation and Heterogeneity by AFM Single Molecule Statistical Analysis
- for more see next page

EDUCATIONAL VIDEOS

Topic	Topic
AFM Principle	Conductive AFM
Non-Contact Mode	Scanning Ion Conductance Microscopy (SICM)
Dynamic Contact EFM (DC-EFM)	Magnetic Force Microscopy (MFM) - *for more see next page*

Contact: Justyna Sliwa pse@parksystems.com

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WEBINAR RECORDINGS

Topic
Nanotechnology in Plastics and Packaging
Surface Plasmon Resonance Spectroscopy Tandem with AFM
Viscoelastic Surfactants and Oilfield Chemicals
Physical Properties of Emergent 2D materials with AFM
2D Nanomaterials for Smart Coatings and Fluids
Electrochemical Capacitors: Fundamentals, Materials, and Advanced Characterization
Nanostructured Polymer Brushes With AFM

EDUCATIONAL WEBINARS

"AFM TECHNIQUES"

Topic
Atomic Force Microscopy PinPoint Nanomechanical Mode for Nanoscale Modulus Mapping – Cantilever Modulus and Applied Force
PinPoint Piezoelectric Force Microscopy
Electrochemical Atomic Force Microscopy (EC-AFM)
PinPoint Nanomechanical Imaging Using Probes of Various Cantilever Stiffness
Scanning Ion Conductance Microscopy (SICM) and Scanning Electrochemical Microscopy (SECM)

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EDUCATIONAL VIDEOS

"How AFM works?"

Topic	Topic
AFM Principle	Scanning Ion Conductance Microscopy (SICM)
Contact Mode	Force Distance Spectroscopy
Non-Contact Mode	Magnetic Force Microscopy (MFM)
Tapping Mode	Force Modulation Microscopy (FMM)
Dynamic Contact EFM (DC-EFM)	Lateral Force Microscopy (LFM)
Electrostatic Force Microscopy (EFM)	NanoIndentation
Conductive AFM	Nanolithograpy
IV Spectroscopy	Scanning Thermal Microscopy (SThM)
Scanning Capacitance Microscopy (SCM)	
Scanning Kelvin Probe Microscopy (KPFM)	

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NANOSCIENTIFIC TALKS

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Topic	Speaker
Nanomechanics & Electrical Characterization	
External Energy Assisted Nanomachining Using Soft AFM Probes	Dr. Jia Deng, Binghamton University - SUNY, NSS US 2019
Atomic Force Microscopies to study Electronic Properties and Strain in Thin Films for Flexible Electronics	Tobias Cramer, University of Bologna, Italy I NSFE 2018
The growth of organic ultra-thin films on silicon oxides with variable vacancy states: a Scanning Force Microscopy approach	Cristiano Albonetti, CRN – ISMN, Italy I NSFE 2018
Detection of Hydrophobic Interactions on Rough Surfaces via Atomic Force Microscopy: from Measurement to Modelling	Urs Peuker, TU Bergakademie Freiberg, Germany NSFE 2018
AFM Methodology	
Chemical Sensitivity for Scanning Probe Microscopy	Lukas Eng, Tech. University Dresden I NSFE 2018
Electrochemical measurements of single nanoparticles	Kim McKelvey, Trinity College Dublin I NSFE 2019
Learning in Fundamental Atomistic Processes Using Suspended Silicon Nanowires	Dr. Ye Tao, Rowland Institute at Harvard I NSS US 2018
3D Nanoscaffold Cantilevers for Potential Applications in High Speed Wafer Scale Imaging	Hoa Le, The Rowland Institute at Harvard, NSS US 2019
Scanning Capacitance Spectroscopy for Dopant Analysis on Nanoscale Semiconductor Devices	Phil Kaszuba, Global Foundries US I NSS US 2019
Measuring Ions and Electrons with Nanoscale Pipettes	Dr. Lane Baker, Indiana University, NSS U 2019
Life Science and Biotechnology	
Revisiting the Early Aggregation of Amyloids by AFM Single Molecule Statistical Analysis	Francesco S. Ruggeri, University of Cambridge I NSFE 2018
Probing the Intersection of Nanotechnology and Biology	Dr. Nathaniel Cady, Colleges of Nanoscale Science & Engineering I NSS US 2019
Metallo-DNA molecules as a tool for nanoscience and nanotechnology	Miguel A. Galindo, CIC, University of Granada I NSFE 2019
AFM Applications in biology and medicine	Malgorzata Lekka, Institute of Nuclear Physics, Poland I NSFE 2019
Organic Interfaces and Semiconductors	
Measurement Challenges arising from New Semiconductor Materials and Structures for Integrated Circuits	Dr. Alain Diebold, SUNY Polytechnic Institute I NSS US 2019
Characterizing photoelectric and ferroelectric properties of materials with scanning probe microscope	Akash Bhatnagar, Centre for Innovation Competence SiLi-nano I NSFE 2019
SPM Study of Tribo-Photovaltaic Effect in Metal, Semiconductor Moving Contacts	Jun Liu, University at Buffalo I NSS US 2019

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